2015 IEEE 21st International On-Line Testing Symposium (IOLTS 2015)

Halkidiki, Greece
6-8 July 2015

IEEE Catalog Number: CFP15OLT-POD
ISBN: 978-1-4673-7906-9

Technical Papers

Session 1	Reliability Evaluation
Date/Time	Monday July 6, 2015 / 10:35 – 11:35
Moderator	S.Hellebrand, *U Paderborn*

Session 2	Posters
Date/Time	Monday July 6, 2015 / 11:35 – 13:00

Session 3	Reliable Filters and Sensors
Date/Time	Monday July 6, 2015 / 14:00 – 15:00
Moderator	Z. Stamenkovic, *IHP*

Session 4	**Fault Tolerant On-Chip Networks**
Date/Time	Monday July 6, 2015 / 15:20 – 16:20
Moderator	A. Grasset, *Thales*

Session 5	**Fault Tolerance**
Date/Time	Monday July 6, 2015 / 16:50 – 17:50
Moderator	G. Georgakos, *Infineon*

Special Session 1	**The Future of Fault Tolerant Computing**
Date/Time	Monday July 6, 2015 / 18:00 – 19:30
Organizers/Moderators	D. Gizopoulos, *U Athens* and D. Alexandrescu, *iRoC*

Session 6	**Error Tolerance and Prediction**
Date/Time	Tuesday July 7, 2015 / 09:00 – 10:00
Moderator	A. Paschalis, *U Athens*

Session 9	Failure Prediction and Diagnosis
Date/Time	Wednesday July 8, 2015 / 12:00 – 13:00
Moderator	E. Ibe, *Hitachi*

Session 10	Memory Reliability
Date/Time	Wednesday July 8, 2015 / 14:00 – 15:00
Moderator	R.Canal, *UPC*